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Optics and photonics — Preparation of drawings for optical elements and systems —

Part 8: Surface texture

*Optique et photonique — Indications sur les dessins pour éléments et
systèmes optiques —*

Partie 8: État de surface



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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

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This document was prepared by Technical Committee ISO/TC 172, *Optics and Photonics*, Subcommittee SC 1, *Fundamental Standards*.

This third edition cancels and replaces the second edition (ISO 10110-8:2010), which has been technically revised.

The main changes compared to the previous edition are as follows:

- a) a drawing notation and interpretation is provided for the following additional areal terms: S_a , S_q , $S_{\Delta q}$, and APSD;
- b) the following terms are explicitly allowed: R_a , R_{sk} , R_{ku} , and ACV , which also required the addition of more definitions, and additional examples.
- c) this edition removes the reference to micro-defects as a method of determining polish grade, and replaces it with specific rms roughness values.

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